

Science and Technology Appointments Made at Energy Department

Energy Secretary James D. Watkins made several announcements concerning key positions under William Happer, who serves as both the science and technology adviser to the secretary and as DOE's director of energy research. As director of energy research, Happer is responsible for a \$3 billion program of research at universities, industry, and laboratories.

The new appointments include Robert M. Simon, previously executive director of the Secretary of Energy Advisory Board (SEAB), as principal deputy director, Office of Energy Research (ER), and James F. Decker, previously acting director of energy research, as deputy director, ER.

Watkins said the changes are designed to better coordinate DOE's management of scientific and technical resources, including the overall vitality of DOE's major laboratories, and to facilitate the transfer of

DOE-funded technology to the private sector:

- Deputy science and technology adviser for civilian laboratories, Antionette Grayson Joseph, former director of field operations management, ER;
- Deputy science and technology adviser for civilian R&D, to be filled;
- Deputy science and technology adviser for defense programs, Warren Chernock, who will remain in DOE's defense programs and focus on DOE laboratories that deal primarily with nuclear weapons R&D;
- Director of technology utilization, Cheri Langenfeld, former director of the Office of Technology Analysis, who will coordinate the development and implementation of DOE's Enhanced Technology Transfer program;
- Director of the office of space, a new office headed by Fenton Carey, who will be responsible for space policy and coordination of DOE's space-related activities; and

■ Director of the office of university and science education, Richard Stephens, who continues in this office which was moved from ER to the Office of the Science Adviser. Stephens will help coordinate DOE's support of mathematics and science education, especially programs in support of the National Education Goals and "America 2000." □

Correction

Fred Nichols' biography on p. 31 in the October 1991 *MRS Bulletin* should have read as follows: He received BS and MS degrees in metallurgical engineering from the University of Kentucky, MS and PhD degrees in metallurgy from Carnegie Institute of Technology, and an MBA from the University of Chicago. □

PSI Delivers . . .

SFM/STM Data Analysis Capability for Science and Industry

PSI's scanning probe microscopes provide the most advanced spectroscopic and quantitative topographic analysis capability in the industry!

For scientific applications, this means 3D-enhanced images for qualitative comparisons of surfaces, and the ability to collect quantitative data for expanded in-depth analysis. For industrial users, it means angstrom scale cross-section and roughness measurements.

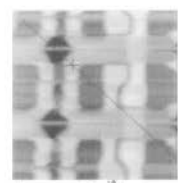
But PSI delivers even more than that. Source code. System electrical schematics. Training, installation and application support. All at no additional cost!

For more information, call today. You'll understand why PSI customers say, "PSI Delivers."

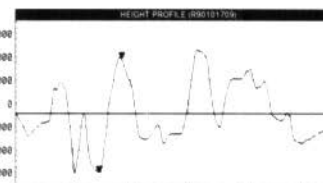
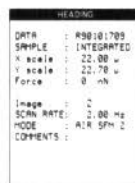


Park Scientific Instruments

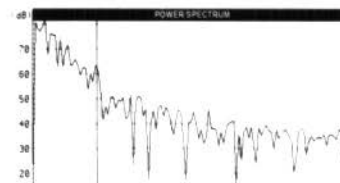
1171 Borregas Ave., Sunnyvale, CA 94089 Tel: 408-747-1600 Fax: 408-747-1601
 In Japan: Hakuto Tel: 03-3225-8910 Fax: 03-3225-9011 In Europe: PSI S.A., Switzerland Tel: 41-22-300-4411 Fax: 41-22-300-4415



Distance: 27.76 μ m



Distance: 1.98 μ m Trace Distance: μ m Height: 8792.00 A Angle: deg: 26.33



Spatial Frequency: 1.926 / μ m Spatial Period: 1.00 μ m

Surface feature heights and widths, roughness parameters and power spectra can be measured along any line, as shown in this SFM image of an integrated circuit.

Circle No. 10 on Reader Service Card.